

<b>Notice of References Cited</b>	Application/Control No. 10/065,663		Applicant(s)/Patent Under Reexamination HU ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,261,917 B1	07-2001	Quek et al.	438/396
*	B	US-6,285,050 B1	09-2001	Emma et al.	257/296
*	C	US-6,570,210 B1	05-2003	Sowlati et al.	257/307
*	D	US-2002/0093780 A1	07-2002	Hajimiri et al.	361/306.1
*	E	US-2002/0113292 A1	08-2002	Appel, Andrew T.	257/532
*	F	US-2003/0003665 A1	01-2003	Nakagawa, Osamu Samuel	438/275
*	G	US-6,528,838 B1	03-2003	Ng et al.	257/306
*	H	US-2003/0062564 A1	04-2003	Kobayashi et al.	257/306
*	I	US-2002/0047154 A1	04-2002	Sowlati et al.	257/307
*	J	US-2003/0117206 A1	06-2003	Ohnakado, Takahiro	327/310
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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